## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | WALKER ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,741,834 B1	05-2004	Godwin, John P.	455/3.01
*	В	US-2004/0198389 A1	10-2004	Alcock et al.	455/456.1
*	С	US-5,797,087	08-1998	Lee, Hyo Chan	455/181.1
*	D	US-2004/0192189 A1	09-2004	Yuhara et al.	455/003.02
*	F	US-6,829,475 B1	12-2004	Lee et al.	455/419
*	F	US-6,347,216 B	02-2002	Marko et al.	455/12.1
*	G	US-2001/0004587 A1	06-2001	Lee, Sang-Seok	455/403
*	Н	US-7,065,333 B2	06-2006	Engstrom, G. Eric	455/184.1
*	1	US-6,980,769 B2	12-2005	Toporski, Todd A.	455/3.01
	J	US-			
	К	US-			
Į TĪ	٦	US-			
	М	US			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

	NON-FATENT DOCUMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.